SOPHISTICATED INSTRUMENTATION CENTRE FOR APPLIED RESEARCH AND TESTING (SICART)

(Under SAIF- Sophisticated Analytical Instruments Facility by DST, New Delhi)



(Sponsored by Department of Science & Technology, Govt. of India, New Delhi) NABL Accredited Laboratory, Certificate No. TC-5124 Sardar Patel Center for Science & Technology Charutar Vidya Mandal Vallabh Vidyanagar – 388120, Dist. Anand, Gujarat, India Phone: +91-2692-234966, +91-2692-238355 E-mail: sicart_cvm@hotmail.com <u>sicartcvm@sicart.res.in</u> Website : www.sicart.res.in

Inauguration Picture of SICART



Major Objectives of SICART

A. Vision:

- 1. To create better societal impact by providing scientific analytical services to the industry and academic institutes perusing scientific research.
- 2. Expansion of basic research areas to its explicit applications.
- 3. To help in technical analysis for institutionalization or developing, standardization and validation of developing methods in order to promising usage of unexplored resources.
- 4. To organize short- and long-term training workshops/programs on the applications and uses of various analytical techniques for researchers/ industrial users with purpose to sort out their academic task on their focused areas.
- 5. To motivate young researchers for generating innovative ideas from the experimental findings.

B. Mission:

- 1. To acquire newfangled sophisticated analytical instruments.
- 2. To develop capability for preventive maintenance, upgradation of the high-end instruments and timely replacement of old facilities.
- 3. Exploring new MOUs and agreements with industries, academic and research centers.
- 4. To carry out industrial or government sponsored research projects.
- 5. To provide consistent consultative approach and help towards solving analytical problems.
- 6. To contribute in effective networking and dissemination of Institute's sophisticated instruments to the scientific community across the state and country in general.

Authorization

- 1. Sophisticated Analytical Instruments Facility Supported by Department of Science & Technology (Govt. of India).
- 2. Recognized by DSIR as a Research Centre.
- 3. Recognized by Gujarat Pollution Control Board as Environmental Auditor, Schedule- I.
- 4. Accredited by National Accreditation Board for Testing and Calibration Laboratories (NABL)
- 5. Recognized by Charutar Vidya Mandal University and Sardar Patel University as Research Centre for Ph.D. study.

Sr. No.	Employee Name	Designation	Qualification
1	Dr. R. H. Parikh	Hon. Director	M. Pharm, Ph.D. (Pharmacy)
2	Dr. K. K. Tiwari	Sr. Scientific Officer	M.Sc (Environment Science) Ph.D. (Ecotoxicology)
3	Dr. M. R. Tiwari	Sr. Scientific Officer	M.Sc. (Inorganic Chemistry) Ph.D. (Industrial Chemistry)
4	Dr. G. R. Chauhan	Sr. Scientific Officer	M.Sc. (Analytical Chemistry) Ph.D. (Chemistry)
5	Mr. Vipul J. Patel	Jr. Scientific Officer	M.Sc. (Solid State Physics)
6	Mr. Vikas A. Patel	Jr. Scientific Officer	M.Sc. (Electronics) PhD Pursuing
7	Ms. Dhanvi Patel	Technical Assistant	M. Sc. (BioTechnology)
8	Mr. Dipen Patel	Technical Assistant	M.Sc. (Analytical Chemistry)
9	Ms. Daxa Patel	Technical Assistant	M.Sc. (Organic Chemistry)
10	Mr. Kartik Patel	Technical Assistant	M. Pharm (Quality Assurance)
11	Dr. Hiral Soni	Technical Assistant	M.Sc., Ph.D. (Biotechnology)
12	Mr. Savan Patel	Trainee Technical Assistant	M.Sc. (Industrial Chemistry) PhD Pursuing
13	Mr. Hardik Parekh	Trainee Technical Assistant	M.Sc. (Environmental Biotechnology), PhD Pursuing

List of Technical Staff

Sophisticated Instrumentation Facility Available in SICART

Field Emiss	sion Gun Scanning Electron Micro	
1. Make: FEI	Ltd Model: Nova Nano SEM 450	
Resolution:	1.0nm at 15kV,1.4nm at 1kV,	
	3.5nm at 100V	Field Emission Gun Scenning
Accelerating Voltage:	20V to 30kV	Electron Microscopy (FEG-SEM) FEI Ltd Madek Hova Nano SEM 450
Beam current:	up to 200nA	
Magnification:	X25 to X10,00,000	
Field Emission Gun:	Ultra-high brightness Schottky emitter	
Major Applications:	Detection and quantification of elements down to boron. Surface analysis of samples such as semiconductor, metals, geological, pharmaceutical, bio- materials, ceramics, etc. Mapping of different metals in samples can be analyzed	
2. Transmissi	on Electron Microscope (TEM) 20	0 kV Technai-20, Phillips, Holland
Electron Source:	LaB6 and Tungsten Filament	
Accelerating Voltage:	200KV	Transmission Electron
Point Resolution:	0.27nm	Microscope (TEM) 200 kV Technai-20, Phillips, Holland
Magnification:	25x to 7,50,000x	
Sample holder	Single tilt	
Sample preparation accessories	Ultramicrotome and ultracutter	
Major Applications	Morphology, crystal structure, particle size, interface structure, crystal defects, Single crystal Diffraction, biological microbes can be studied.	

5.	RANSMISSION ELECTRON MICR c, Talos F200i S/TEM	OSCOPE (HR-TEM), Thermo Fisher
Electron	Schottky Field emitter (Field	
Source:	Emission Gun)	
Resolution:	Line Resolution 0.10 nm, Point Resolution less than 0.25 nm or less	
Magnification: FEG-TEM Magnification 50x to 1Mx		
STEM Detector: High Angle Annular Dark Field Detector (HAADAF)		
STEM Resolution:	less than 0.16nm	
STEM Magnification	Up to 330 Mx	
EDS or EDAX:	Bruker X Flash 6 30 EDS Detector	
Camera:	4K X 4K Ceta 16M Camera	
Major Application Morphology, crystal structure, particle size, interface structure, crystal defects, Single crystal Diffraction, biological microbes, pharma samples, thin films, catalysts, Nanoparticles, polymer samples can be studied. Quantitative Elemental analysis and elemental		
	-	
Inductiv	Mapping can be done on this facility.	n Spectrometer (ICP- OES) Perkin Elmer.
4. USA, A	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission	n Spectrometer (ICP- OES) Perkin Elmer,
4	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission	Inductively Coupled Plasma
4. USA, Av	Mapping can be done on this facility. rely Coupled Plasma Optical Emission vio 200	
4. USA, Av RF frequency: RF power:	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission Yio 200 40MHz 1000 to 1500 watts (Power	Inductively Coupled Plasma Spectrometer (IDP-UES) (Perkin Elmer, USA
4. USA, Av RF frequency: RF power: Pump:	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission Yio 200 40MHz 1000 to 1500 watts (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml increments	Inductively Coupled Plasma Spectrometer (IDP-UES) (Perkin Elmer, USA
4. USA, Av RF frequency: RF power:	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission Yely 200 40MHz 1000 to 1500 watts (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to	Inductively Coupled Plasma Spectrometer (IDP-UES) (Perkin Elmer, USA
4. USA, Av RF frequency: RF power: Pump:	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission vio 200 40MHz 1000 to 1500 watts (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml increments Charged Coupled Device (CCD)	riterively Caupied Pissme Spectrometer (ICP-DES) DPerkin Ener, ISA Perkin Eliner, Avia 200
4. USA, Av RF frequency: RF power: Pump: Spectrometer: Range:	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission Yely Coupled Plasma Optical Emission Yely Coupled Plasma Optical Emission Yely Coupled Plasma Optical Emission Yely Coupled Device (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml increments Charged Coupled Device (CCD) Array Detector	Inductively Coupled Pasma Spectrameter (DP-UES) Dervin Elmer, USA
 4. USA, Av RF frequency: RF power: Pump: Spectrometer: Range: Resolution: 	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission vio 200 40MHz 1000 to 1500 watts (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml increments Charged Coupled Device (CCD) Array Detector 165 – 900 nm <0.009 nm @200nm	Indertively Coupled Plasma Spectranetar (ICP-DES) Devin Ener, ISA Perine Eliner, Avia 200
 4. USA, Av RF frequency: RF power: Pump: Spectrometer: 	Mapping can be done on this facility. Yely Coupled Plasma Optical Emission vio 200 40MHz 1000 to 1500 watts (Power efficiency greater than 81%) 4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml increments Charged Coupled Device (CCD) Array Detector 165 – 900 nm <0.009 nm @200nm	Indertively Coupled Plasma Spectranetar (ICP-DES) Devin Ener, ISA Perine Eliner, Avia 200
4. USA, Av RF frequency: RF power: Pump: Spectrometer: Range: Resolution:	Mapping can be done on this facility.Yely Coupled Plasma Optical Emissionvio 20040MHz1000 to 1500 watts (Power efficiency greater than 81%)4 Channel peristaltic pump; 0.2 to 7.0 ml/min in 0.1ml incrementsCharged Coupled Device (CCD) Array Detector165 – 900 nm <0.009 nm @200nm	Indertively Coupled Plasma Spectranetar (ICP-DES) Devin Ener, ISA Perine Eliner, Avia 200
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5. X- Ray Diffractome	eter (XRD) Philips, Holland, X-pert	: MPE
Source:	Cu target X-Ray tube	1
X-Ray Power:	2KW	1
Detector:	Xe-filled Proportional detector	-7
Software:	JCPD data base for powder diffractometry	h
2 O Measurement range:	2 to 136	18
Diffractometer radius:	130 to 230mm	11
Major Applications	X-ray diffraction is widely used to identify crystalline phases, measure crystallite sizes, lattice parameters, orientation and provide quantitative phase analysis and atomic coordinates.	



Source:	Cu target X-Ray tube
X-Ray Power:	2KW
	LYNXEYE XE-T is based on
Detector:	silicon strip technology
Software:	DIFFARAC. EVA
20 Measurement	
range:	130 to 230mm
Diffractometer	2 to 136,
radius:	
Major Applications : X-	The D8 Advanced is all-purpose
	Ray analyzer which is configured
	for all powder diffraction
	application, Including phase
	identification, quantitative phase
	analysis, reitveld refinement and
	structure analysis.

7. Wavelength	Dispersive-X-Ray Fluorescence (WD-XRF)
Description:	4Kw WD-XRF sequential basic system	Vaciangih-Disparsite X-ray Ruerescence Spectrometry (VII-XRF), Notel: AlxaMXK, Maie: FAMorical
X ray tube:	Ultra thin Be window (75µm)	
Detectors:	Scintillation and flow counter detection	
	Omnian software	
Software:	TOXAL module	
	WROXI Mineral and mining Modules.	
Major Applications:	XRF can be used to analyze elemental	
	composition from metals, cement, Soil	
	samples, Mining, Steel, Ceramic and	
	glass manufacturing, Metallurgy,	
	Hazardous waste analysis, Petroleum	
	industry, geological samples, ceramic,	
	glass industries, pharmaceuticals,	
	plastics and food industries.	
	NMR Spectrometer (FT-NMR) Model- Bruk vance III, Topspin 2.1	ker,
Liquid and Solid mult		400 MHz FT-NMR Spectrometer
Single Chip RF gener	ation	
Timing Resolution	12.5 ns	8.8
Minimum event time	e 25 ns	
Highest Phase		
resolution	(0.0055°)	
Highest Frequency		
resolution	(0.005 Hz)	
Solid nucloi	(31P ,29Si ,23Na ,27Al ,51V,71Ga,	
Solid nuclei	119Sn ,201Pb)	
	NMR is useful for structure	
Major Applications		
	polymer compounds.	

9. Fourier Transform Infrared Spectrometer (FTIR) Perkin Elmer USA: Spectrum-GX		n Elmer,	
Nor	mal range:	4000-400 cm ⁻¹	
Ope	erating Mode:	MIR	
Scar	nning range:	4000-400 cm ⁻¹	
Scar	n time:	20scan/second	
Reso	olution:	0.15cm ⁻¹	
Sing	gle Beam/Ratio:	Single, Detector: MIRTGS	
Maj	or Applications:	It is used for qualitative and quantitative	
		analysis for organic and inorganic and	
		pharmaceutical samples.	-



^{10.} UV-VIS-NI	R Spectrometer, Perkin Elmer, USA, Lambda 19	
Wavelength	185-3200 nm for	
	Absorbance/Transmission and 200-	
Range:	2500 for Reflectance	
Ratio Recording Lamp:	Halogen (VIS/NIR)	
Detectors:	Photomultiplier tube for UV/Vis	- In-
Solid sample	Tungsten-	-
attachment:	Lead-Sulphide cell (PbS) for NIR	
Double Beam	Double Monochromator, Deuterium (UV)	
Major	To find out wavelength maxima, unknown	-
Applications :	sample concentration, band gap of the	
	semiconductor crystal, optical density,	
	materials optical properties and its	•
	concentration.	



11. LC-MS-MS (LCQ Fleet, TSQ Quantum Access) Thermo fisher scientific, USA		
LCQ fleet and TS System	SQ Quantum Access with Surveyor plus HPLC	LC-MS-HS (LCD Fast, TSD Quantum Access) Thermo Fishers Scientific
Mass range:	LCQ Fleet: 50-2000 Daltons, TSQ Quantum Access: 30-3000 Daltons	
Pump: Dual piston delivery system, built-in vacuum degasser.		
Pressure range:	0 to 5800 PSI (0 to 400 bar) at flow rates up to 2 ml/min.	
Operating temperature:	5°C to 95°C.	
Major Applications:	Compound detection and structural identification of drugs, organic intermediate compound and non-volatile compounds, natural products, pharmaceuticals, environmental samples, clinical and forensics research samples.	
Series-200	ormance Liquid Chromatography (HPLC) Perk	in Elmer, USA,
Quaternary gradie Flow rate	1 to 2 ml/min	
Variable operation pressure	ng back 6200 PSI	
Column	C-18, C-8 column	
Detectors:	Photo Diode Array (PDA), UV- Visible and Fluorescence Detector	
UV- Visible detec Range:	etor 190nm to 800nm	
PDA detector rai	nge 200 to 800nm	

Non- volatile compound detection

from pharma, environment, forensic,

clinical, food beverage samples, etc.

200nm to 900nm

0.0001 to 2.0 AUS

Florescence Detector

Sensitivity range

Major Applications:

range

13. Gel Permeation Perkin Elmer, U	Chromatography (GPC)	
	55A; 56H65-200	
Column:	PL gel, Mixed-B, Mixed-D.	
Molecular Weight distribution	Range: 500-300000gm/mol	
Detector:	Refractive Index (RI)	
Major Applications:	Determinations of Molecular weight of Polymer samples (Mn & Mw), Polydispersity.	
14. Camag-Switzerl Automatic applicator (I	nce Thin Layer Chromatograph (HP and WinCat Linomat-5) of selectable sample	FLC)
14. Camag-Switzerl Automatic applicator (L volume.	and WinCat	FLC)
14.Camag-SwitzerlAutomatic applicator (Lvolume.GMP, GLP compliant in	Linomat-5) of selectable sample mage plate scanner-3 and	Im
14.Camag-SwitzerlAutomatic applicator (Lvolume.GMP, GLP compliant isdocumentation (reproster	Linomat-5) of selectable sample mage plate scanner-3 and er-3) system	
14. Camag-Switzerl Automatic applicator (L volume.	Linomat-5) of selectable sample mage plate scanner-3 and	Im

15. Gas Chromatography with Head Space Perkin Elmer, USA, Auto System XL

	FID (100 °C - 450°C),
Detector:	TCD (100 °C - 350°C) Detector
	NPD and ECD Detector

Useful for finding % purity and impurity profile in solvents, gases (like **Major Applications:** methane, carbon dioxide, nitrogen, etc.) Petroleum products, Flavors, Drugs, Pesticides, etc.



^{16.} Gas Chromatograph with mass spectroscopy (GC-MS) Perkin Elmer, USA, System XL with NIST Library

Analyser:	Single Quadrupole with prefilter
Mass range:	20-610 Daltans (amu)
Mass stability	0.1m/z mass accuracy over 48 hours
Ionization modes:	Electro ionization positive / negative,
ionization modes.	chemical ionization
Major Applications:	Identification of volatile organic
	compounds from Environmental,
	Flavors, Fragrances, Pharmaceuticals,
	Organic, Petrochemicals, Fine
	Chemicals samples, etc.



17.	Particle Size A	nalyzer (PSA), Symantec-HELOS-BF, Ger	many
Laser	Diffraction part	icle size determination	Terrere and the second s
Syster range	m Particle size	0.1μm to 875 μm	
Accur	acy for Dry and	Liquid sample	
Majo	r Applications:	To find the size of particles, particle size distribution in the suspension, emulsions & powder material.	
18. Analy	CHN/S/O Elen Elmer, USA yzed Elements:	nental Analyzer 2400 Series II, Perkin Carbon, Hydrogen, Nitrogen, Sulfur	
Opera Mode	ating	and Oxygen CHN, CHNS and OXYGEN	
Accu	racy:	0.3 % abs	
Analy	vsis Time:	6 to 8 minutes per sample	M.
Majo	r Applications:	To analyze the concentration & percentage of C,H,N,S & O from powder samples of newly	

19. Thermal Anal	ysis (DSC, STA), Perkin Elmer, USA	
Model:	DSC-8000	
Temperature Range:	(-35 °C to 400 °C)	
Heating Rate:	0.1 to 100 °C / min	
Sensitivity:	0.1m gm (0.0001mg)	
Atmosphere:	Nitrogen	
Major Applications:	 Differential scanning calorimeter measures Melting, Crystallization, Glass Transitions Temperature, Crystallinity, Specific heat, Polymorphism, Kinetic Studies, Curing Reaction. Used in characterization of polymorphism in pharmaceuticals, Characterization of pharmaceuticals formulations. 	
20. Thermal Anal	ysis (STA), Perkin Elmer, USA	
Model-	STA 8000	
Specification -	Simultaneous analysis of TG with DTA mode and DSC.	
Temperature Range:	30°C to 1000°C	
Temperature Accuracy:	± 0.2 °C	
Heating Rate:	0.1 to 100 °C / min	
Atmosphere:	Nitrogen	
Major Applications:	Widely used in polymer,	
	pharmaceuticals, cosmetics industry etc.	

21. Thermal Ana	lysis System (TGA), Perkin Elmer, USA	
Model	TGA-4000	
Temperature range:	Ambient to 1000 °C	
Heating Rate:	0.1 to 100 °C / min	
Atmosphere:	Nitrogen or Air	
Major Applications:	To characterize multicomponent materials. Widely used in polymer, pharmaceuticals, metals, metal oxides, cosmetics industry etc.	Perkinsense Tech.4000 (Thermogravimetric Analyzer)
22. Universal Tes	ting Machine (UTM), Shimadzu, Japan, A	AG 100 KNG
Capacity:	100KN (10000 kgf)	
Load measuring accuracy:	$\pm 0.5\%$ of indicated load	
Cross head speed range:	0.05 to 1000mm/min	
Cross head speed precision:	<u>+</u> 0.1	
Effective test width:	575nm	
	575nm 100kN, 5kN, 1kgf	
Load cell of		
Load cell of	100kN, 5kN, 1kgf	
Effective test width: Load cell of Major Applications:	100kN, 5kN, 1kgf To measure Tensile strength of Fabrics,	
Load cell of	100kN, 5kN, 1kgf To measure Tensile strength of Fabrics, Tires, Cords, Polymers, Plastics, Rubber,	

Total Organic Carbon (TOC) Analyzer Shimadzu, Japan, TOC-VCSN/TNM-1

Measurement range of Total Carbon:	0 to 25000 mg/l
Inorganic Carbon:	0 to 3000 mg/l;
Total Nitrogen:	0 to 4000 mg/l
Measurement Time:	10 minute per sample
Major Applications:	For rapid measurement of even small quantity of organic matter in samples of wastewater, soil, sludge, sediments etc., and determination of degree of contamination.

23.



24. Ambient Air Quality Monitoring Mobile Van, Environment SA, France

		Carbon monoxide, Total
Measurement of:		hydrocarbons, Oxides of nitrogen,
		Ozone, Particulate matter, Sulphur
		dioxide and meteorological
		parameters
		Monitoring emissions from stationary
		sources, Measurement of environment
		quality in the workplace, Continuous
Major Applications:		Ambient Air Quality monitoring,
		Assessment of hazardous situation in plant
		operations, and characterization of
		atmospheric stability



		Water and wastewater analysis
	Environmental	Solid waste and soil analysis
25.	Analysis/ Monitoring/	Stack pollution monitoring
	Auditing Facilities	Environmental Audit and Environmental Consultancy Services
		Environmental Research & Development

Contact for more information:

Dr. R. H. Parikh, Hon. Director

Sophisticated Instrumentation Centre for Applied Research and Testing (SICART), (Sponsored by Department of Science and Technology, Govt. of India, New Delhi) Sardar Patel Centre for Science and Technology Vallabh Vidyanagar – 388120, Dist: Anand, Gujarat, INDIA Phone: +91-2692-234966, +91-2692-238355 E-mail: directorsicart@gmail.com sicart_cvm@hotmail.com sicartcvm@sicart.res.in Social Media pages: Facebook: sicart cvm Instagram: sicartcvm